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Technical specifications:

Analytical range of elements: From sodium(Na) to uranium(U)

Analytical range of element contents: 1ppm~99.99%

Ability to analyze simultaneously: Can analyze 24 elements simultaneously

Detection limit: The detection limit can reach 1ppm for hazardous substances (Cd/Pb/Cr/Hg/Br) ruled in RoHS directive.

Range of functions: Used for RoHS substances detection, mineral aggregate analysis, plating thickness analysis, full

element analysis, one machine for multiple purposes

Measurement of plating thickness: Can test plating thickness as thin as 0.005 $\,\mu$ m and analyze plating of more than 11 layers

Analysis accuracy: 0.05%

Measuring object: powder, solid and liquid

Measurement time: 60~200s

Ambient temperature range: 15~30℃

Relative humidity: ≤70%

Revolution: Energy revolution is 140±5eV (SDD detector made in Germany)

Working voltage: AC 110V/220V

Instrument power: 200W

Tube voltage: 5~50kV

Tube current: 50~1000 µ A

3-D super-large sample chamber design and the size is Φ 320mm \times 180mm

Weight: 75kg

Conciseness!

Simple?

Smoothness...





X-ray tub

High and low voltage power supplies

Amplifier circuit

Double-laser positioning system

The sample to be analyzed can be amplified 100 times 😉

Observe detected part clearly

PC and ink-jet printer

Si-PIN semiconductor detector 🗖

High-resolution camera, and unique light path enhancement system Special software, with friendly operation interface



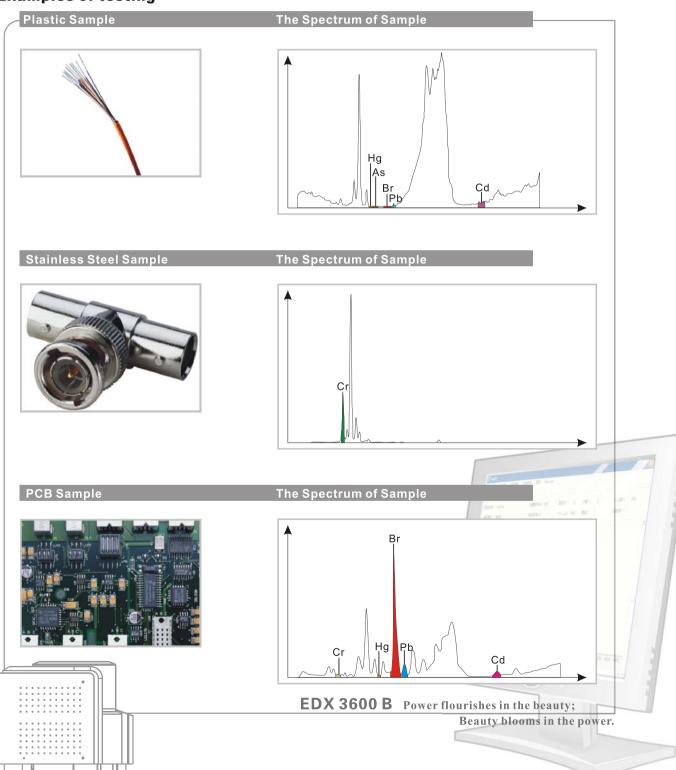
A combination of inner and outer cultivation is the nature of HIGH QUALITY instruments.

HIGH-PERFORMANCE SYSTEM operates with gorgeous appearance



With the most advanced technology in the field of X-ray fluorescence detection—signal-to-noise enhancer(SNE), EDX 3600B decreases the detection limit greatly through lowering the interference of circuit and various ambient noises, and at the same time the interference from other elements has been brought down to a minimum and accuracy of detection is further increased. SNE can raise the signal processing ability of EDX3600B 25 times efficiently, and obvious results can be obtained especially while detecting Pb and Cd.

Examples of testing



What is RoHS and WEEE Directive?

On 13 Feb, 2003, European Union issued Directive 2002/95/EC on RoHS and Directive 2002/95/EC on WEEE. The EU directives RoHS and WEEE have been implemented. New electrical and electronic equipment put on the market from 1 July 2006 shall not contain lead(Pb), mercury(Hg), cadmium(Cd), hexavalent chromium(Cr⁶⁺), polybrominated biphenyls(PBBs) or polybrominated diphenyl ethers(PBDEs).

Testing standards for substances restricted by RoHS Directive

Hazardous substances	Standards (mg/kg)
Cd	100
Pb	1000
Hg	1000
Br(PBBs & PBDEs)	1000
Cr ⁶⁺	1000

Restricted substances and their typical uses

Pb		
Solders		
Paints	Pigments and driers	
Glass materials	Pb is allowed in fluorescent lamp	
Ceramic materials	Pb is allowed in certain electronic ceramic materials	
Iron, aluminum and copper mate	erials A certain amount of Pb is allowed	
Plastic	PVC stabilizer and pigments	
Batteries	Pb is allowed in acidic batteries for vehicles	

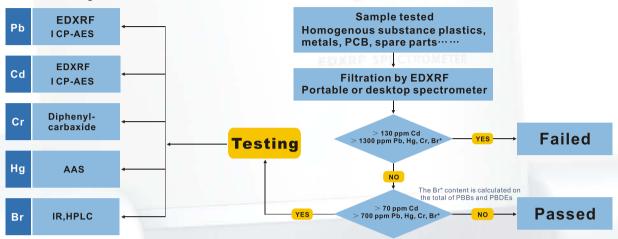
Cd	
Plastics	Stabilizer and pigments
Solders	Seldom used
Ceramic materials	Seldom used
Connectors	
Batteries	Cd is allowed in Ni-Cd batteries
	Optical sensors and solar cell panels

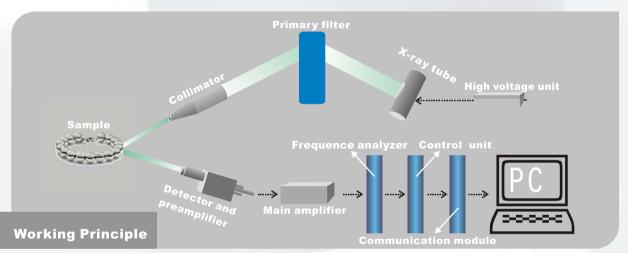
Hg	
Batteries	Prohibited (see battery directive)
Connectors	Relays and sensitive switches
Fluorescent lamps	A certain amount of Hg is allowed

Cr VI +	
Passivation layers	Commonly used for naked metal surfaces to enhance adhesion of plating layers
Anti-corrosive plating layers	Painting and plating layers
Chrome plating layers	Plating layer of chromium metal is not under control
Plasticizer	Commonly used to plastics plating process but not final products
PBB&PBDE	

Brominated flame retardants

The analytical method of filtration for RoHS substances





Characteristic X-rays of elements

Each element will emit X-ray with its own energy when it is excited, this characteristic X-ray is called X-ray fluorescence. That is the basis for analysis.

Scatting

It is the background of the spectrum.

Photoelectron

It is what the detector analyzes.

The X-ray fluorescence intensities of interested elements in the sample are I_1 , I_2 , I_3 , I_4 , I_5 etc. And the element content is a function of X-ray fluorescence intensity I of the element. The general formula is as follows:

 $C=f(I_1, I_2, I_3, I_4, I_5....)$

The function is too complicated to calculate, and the empirical formula is as follows:

 $C=K_1I_1+K_2I_2+K_3I_3+K_4I_4+K_5I_5\cdots\cdots$

C means

The content of element in the sample.

$I_1, I_2, I_3 \cdots \cdots mean$

X-ray fluorescence intensities of elements in the sample respectively.

$K_1, K_2, K_3 \cdots mean$

Coefficients to be calculated.

The coefficients K_1, K_2, K_3can be determined with the samples of known contents though the establishment of scale merit.